

TYPE	Bvdss	Rdson	Id
ZY70N65	65V	10mΩ	70A

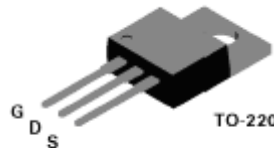
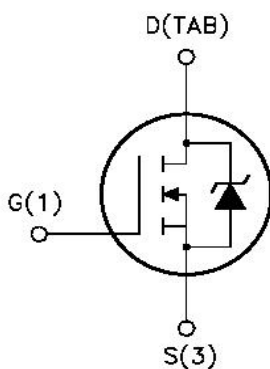
Typical Rdson = 8.5mΩ

Exceptional dv/dt Capability

100% Avalanche Tested

Application Oriented

Characterization



DESCRIPTION

This Power Mosfet series realized with SZY Corp. DMOS technology trench process has specifically signed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced high-efficiency isolated DC-DC Converters for Telecom and Computer application. It is also intended for any application with low gate charge drive requirements.

APPLICATIONS

HIGH-EFFICIENCY DC-DC CONVERTERS
 DC MOTOR CONTROL
 UPS
 AUTOMOTIVE ENVIRONMENT



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
Vds	Drain-Source Voltage (Vgs=0)	65	V
Vdgr	Drain-gate Voltage (R _{Gs} = 20 KΩ)	65	V
Vgs	Gate- source Voltage	±20V	V
I _d (a)	Drain Current (continuous) at T _c = 25 °C	70	A
I _d	Drain Current (continuous) at T _c = 100 °C	42	A
I _{DM} (b)	Drain Current (pulsed)	240	A
P _{tot}	Total Dissipation at T _c = 25 °C	110	W
	Derating Factor	0.7	W/°C
dv / dt (1)	Peak Diode Recovery voltage slope	4	V/ns
E _{as} (2)	Single Pulse Avalanche Energy	360	mj
T _{stg}	Storage Temperature	-55~175	°C
T _j	Max. Operating Junction Temperature		

(a) Current limited by package

(b) Pulse width limited by safe operating area

(1) ISD ≤60A, di/dt ≤400A/us, VDD ≤24V, T_j ≤T_{JMAX}.

(2) Starting T_j = 25 °C, I_D = 30A, VDD = 30V

THERMAL DATA

R _{thj-case}	Thermal Resistance Junction-case	Max	1.36	°C / W
R _{thj-amb}	Thermal Resistance Junction-ambient	Max	63	°C / W
T _i	Maximum Lead Temperature For Soldering Purpose	Typ	300	°C

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Bvdss	Drain-source Breakdown Voltage	I _D = 250 uA V _{GS} = 0	65			V
I _{dss}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{ds} = Max Rating V _{ds} = Max Rating T _c = 125 °C			1 10	uA uA
I _{gss}	Current (V _{DS} = 0)	V _{GS} = . 20V			±100	nA

ON

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} I _D = 250uA	2	3	4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10V I _D =30A		8.5	10	mΩ



DYNAMIC

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Gfs	Forward Transconductance	VDS = 15V ID=30A		20		S
Ciss	Input Capacitance	VDS = 25V, f = 1 MHz, VGS=0		1810		PF
Coss	Output Capacitance			360		PF
Crss	Reverse Transfer Capacitance			125		PF

ELECTRICAL CHARACTERISTICS

SWITCHING ON

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
td (on)	Turn-on Delay Time	VDD=30V, ID=30A, Rg=4.7Ω		16		ns
tr	Rise Time	VGS=10V (Resistive Load, Figure 3)		108		ns
Qg	Total Gate Charge	VDD = 48V ID = 60 A VGS= 10V		49	66	nc
Qgs	Gate-Source Charge			18		nc
Qgd	Gate-Drain Charge			14		nc

SWITCHING OFF

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
td (off)	Turn-off Delay Time	VDD=30V, ID=30A, Rg=4.7Ω		43		ns
tf	Fall Time	VGS=10V (Resistive Load, Figure 3)		20		ns

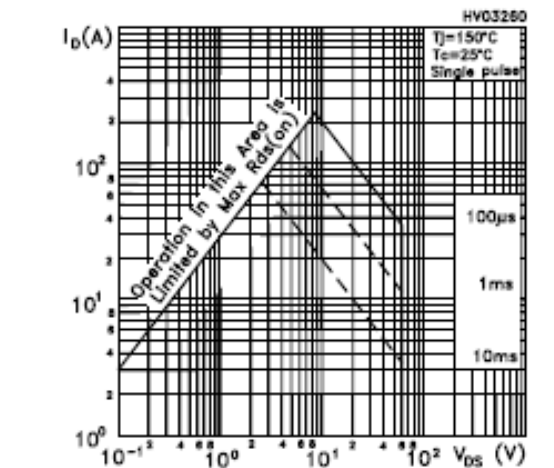
SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
ISD	Source-drain Current				60	A
ISDM (1)	Source-drain Current (pulsed)				240	A
VSD (a)	Forward On Voltage	ISD = 60 A VGS = 0			1.3	V
trr	Reverse Recovery Time	ISD = 60 A VDD = 25 V		73		ns
Qrr	Reverse Recovery Charge	di/dt = 100A/us Tj= 150 °C		182		nc
IRRM	Reverse Recovery Current	(see test circuit, Figure 5)		5		A

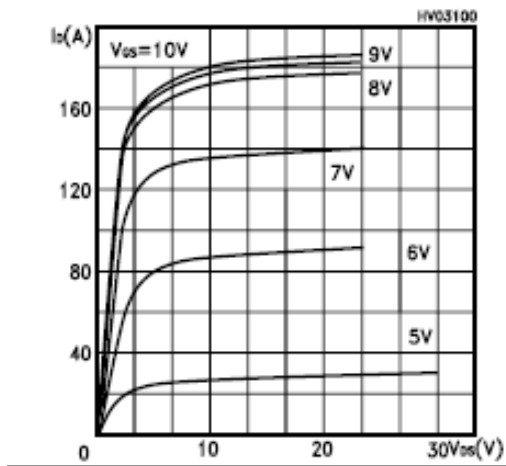
(1) Pulse width limited by safe operating area

(a) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

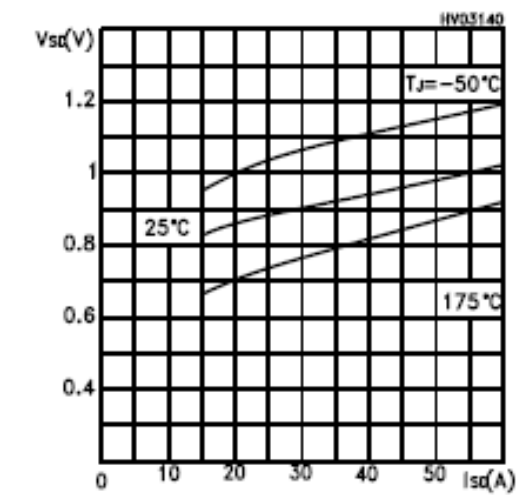
Safe Operating Area



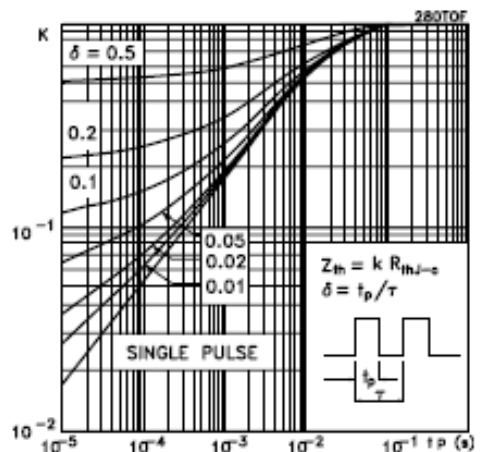
Output Characteristic



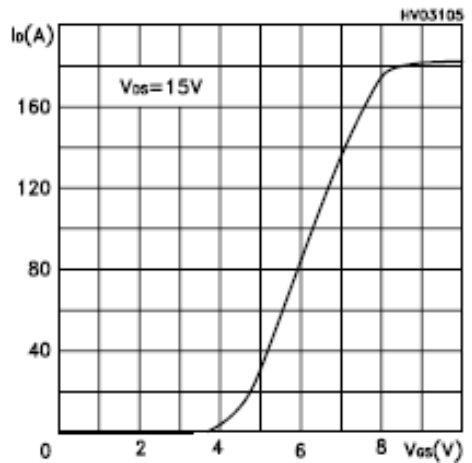
Source-drain diode forward characteristics



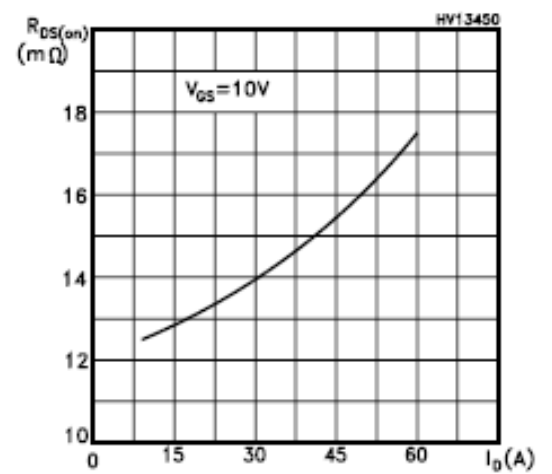
Thermal Impedance



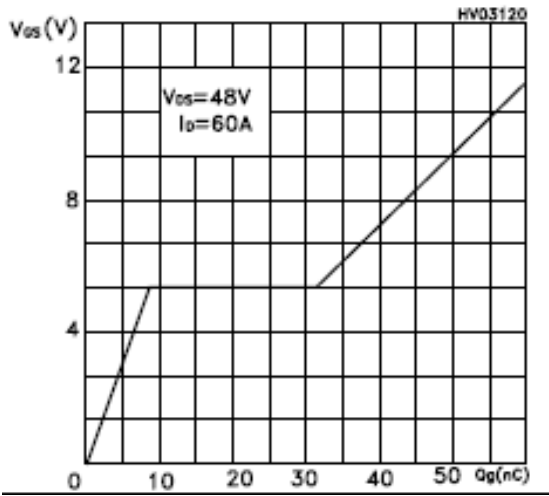
Transfer Characteristics



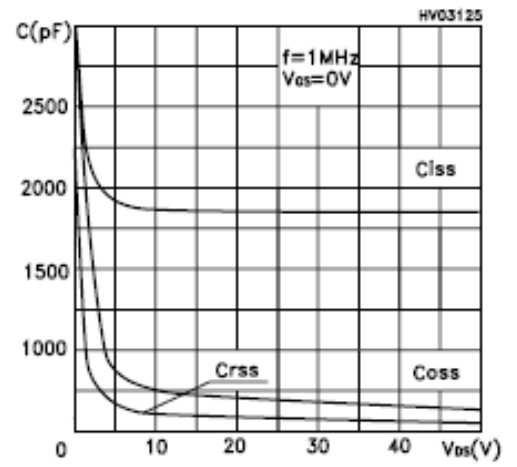
Static Drain-source On Resistance



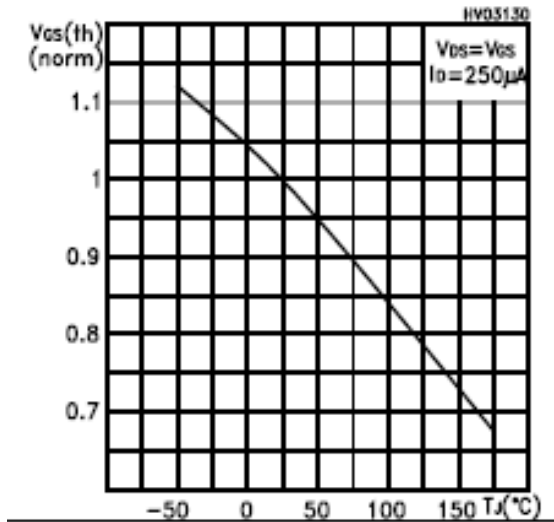
Gate Charge vs Gate-source Voltag



Capacitance Variation



Normalized Gate Threshold Voltage vs Temperature



Normalized on Resistance vs Temperature

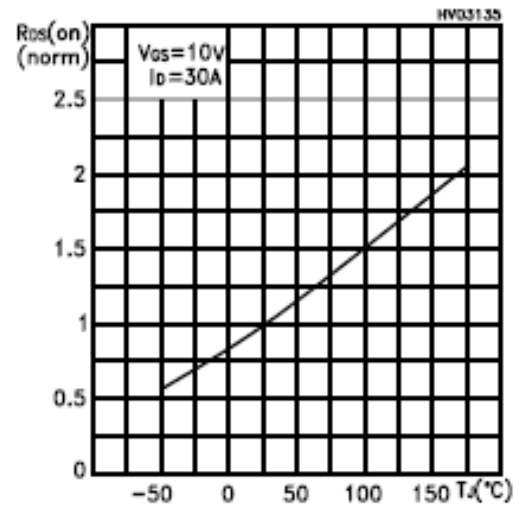


Fig. 1: Unclamped Inductive Load Test Circuit

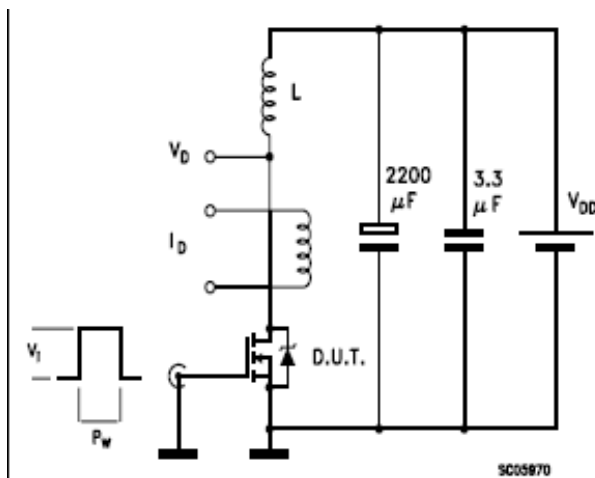


Fig. 2: Unclamped Inductive Waveform

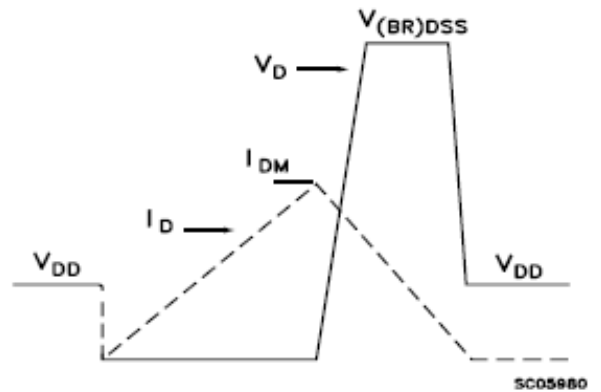


Fig. 3: Switching Times Test Circuits For Resistive Load

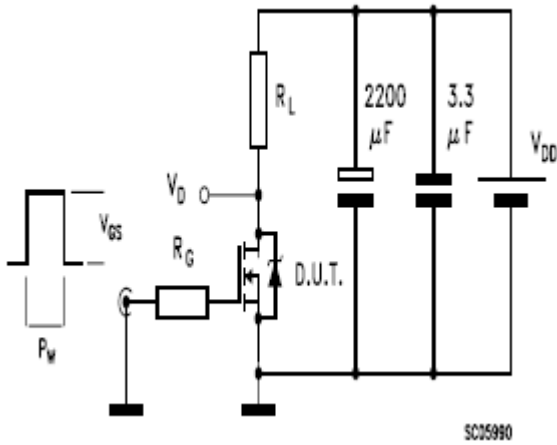


Fig. 4: Gate Charge test Circuit

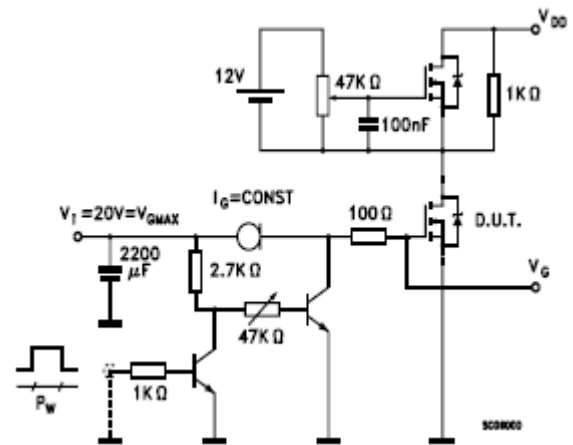
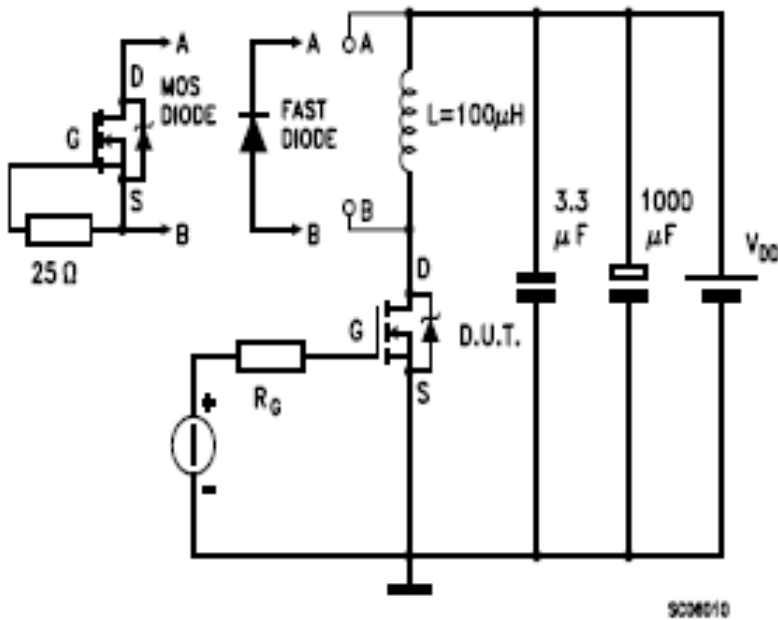
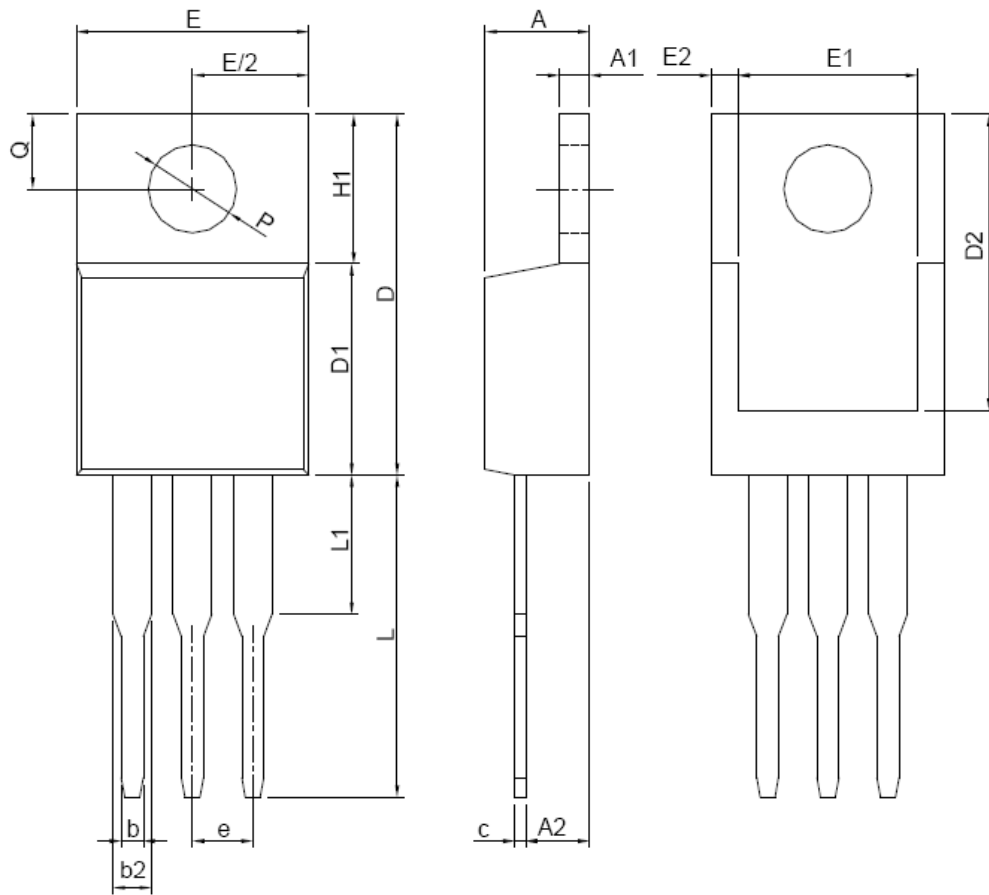


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



TO-220 POD DATA



Dim	Millimeters		Inches	
	Min.	Max.	Min.	Max.
A	3.56	4.83	0.140	0.190
A1	0.51	1.40	0.020	0.055
A2	2.03	2.92	0.080	0.115
b	0.38	1.02	0.015	0.040
b2	1.14	1.78	0.045	0.070
c	0.36	0.61	0.014	0.024
D	14.22	16.51	0.560	0.650
D1	8.38	9.02	0.330	0.355
D2	12.19	12.88	0.480	0.507
E	9.65	10.67	0.380	0.420
E1	6.86	8.89	0.270	0.350
E2	-	0.76	-	0.030
e	2.54 BSC		0.100 BSC	
H1	5.84	6.86	0.230	0.270
L	12.70	14.73	0.500	0.580
L1	-	6.35	-	0.250
P	3.53	4.09	0.139	0.161
Q	2.54	3.43	0.100	0.135